

L Number	Hits	Search Text	DB	Time stamp
2	1	("6191846").PN.	USPAT	2004/06/15 13:47
3	2	((("6191846") or ("5438413")).PN.	USPAT	2004/06/15 15:05
4	33	semiconductor and (misregistration) and overlay and defects	USPAT	2004/06/15 15:05
5	1	semiconductor and (misregistration) and overlay and defects and (wafer adj stage)	USPAT	2004/06/15 16:36
6	1		USPAT	2004/06/15 15:25
7	1057	(438/14).CCLS.	USPAT	2004/06/15 16:36
8	570	(438/15).CCLS.	USPAT	2004/06/15 16:36
9	90	(wafer adj stage) and defect and registration	USPAT	2004/06/15 16:37
10	126	(wafer adj stage) and defect and registration	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 16:38
11	283	scatterometer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 16:38
12	116	scatterometer and stage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 16:38
13	60	scatterometer and stage and defect	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 16:38
14	4	scatterometer and stage and defect and registration	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 16:38
15	0	scatterometer and stage and defect and (overlay adj registration)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/15 16:38
-	1	("6673637").PN.	USPAT	2004/06/15 13:47